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| Notice of References Cited | Application/Control No. 10/620,175 | Applicant(s)/Patent Under Reexamination STEMPIEN ET AL. | |
| | Examiner Edgardo San Martin | Art Unit 2837 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-6,438,839 | 08-2002 | Hardesty et al. | 29/890 |
| | B | US-5,293,744 | 03-1994 | Imagawa et al. | 181/240 |
| | C | US-6,561,722 | 05-2003 | Dudko et al. | 29/419.2 |
| | D | US-6,247,552 | 06-2001 | Kovar et al. | 181/240 |
| | E | US-5,966,813 | 10-1999 | Durand, Robert D. | 219/611 |
| | F | US-5,813,264 | 09-1998 | Steingroever, Erich | 72/56 |
| | G | US-5,220,789 | 06-1993 | Riley et al. | 181/240 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|--------------------|----------------|
| | N | JP 04356322 A | 12-1992 | Japan | ENOMOTO et al. | B21D 39/04 |
| | O | JP 56091991 A | 07-1981 | Japan | AKIZUKI, TOUSHIROU | B23K 20/06 |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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